
**Surface chemical analysis — Auger
electron spectroscopy and X-ray
photoelectron spectroscopy — Methods
used to determine peak intensities and
information required when reporting
results**

*Analyse chimique des surfaces — Spectroscopie des électrons Auger
et spectroscopie de photoélectrons par rayons X — Méthodes utilisées
pour la détermination de l'intensité des pics et informations requises
pour l'expression des résultats*



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